

# N-Channel 200 V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	200	)			
R <sub>DS(on)</sub> (Ω)	V <sub>GS</sub> = 10 V	1.2			
Q <sub>g</sub> (Max.) (nC)	8.2				
Q <sub>gs</sub> (nC)	1.8				
Q <sub>gd</sub> (nC)	4.5				
Configuration	Single				

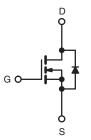
#### **FEATURES**

- Available in tape and reel
- Dynamic dV/dt rating
- Repetitive avalanche rated
- Fast switching
- Ease of paralleling
- Simple drive requirements









N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS ( $T_C$	= 25 °C, unl	ess otherwis	se noted)		
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			$V_{DS}$	200	V
Gate-Source Voltage			$V_{GS}$	± 20	v
Continuous Drain Current	V -140V	$T_{\rm C} = 25  ^{\circ}{\rm C}$ $T_{\rm C} = 100  ^{\circ}{\rm C}$	I <sub>D</sub>	1.0	
Continuous Drain Current	VGS at 10 V	T <sub>C</sub> = 100 °C		0.8	Α
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	5.0	
Linear Derating Factor				0.025	W/°C
Linear Derating Factor (PCB Mount) e				0.017	
Single Pulse Avalanche Energy b			E <sub>AS</sub>	50	mJ
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	0.96	Α
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	0.31	mJ
Maximum Power Dissipation	$T_C = 25 ^{\circ}\text{C}$ $T_A = 25 ^{\circ}\text{C}$		P <sub>D</sub>	3.1	W
Maximum Power Dissipation (PCB Mount) e				2.0	v
Peak Diode Recovery dV/dt <sup>c</sup>			dV/dt	5.0	V/ns
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C
Soldering Recommendations (Peak Temperature) d	for	10 s		300	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b.  $V_{DD}$  = 50 V, starting  $T_J$  = 25 °C, L = 81 mH,  $R_G$  = 25  $\Omega$ ,  $I_{AS}$  = 0.96 A (see fig. 12). c.  $I_{SD} \le 3.3$  A,  $dI/dt \le 70$  A/µs,  $V_{DD} \le V_{DS}$ ,  $T_J \le 150$  °C.
- d. 1.6 mm from case.
- e. When mounted on 1" square PCB (FR-4 or G-10 material).



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient (PCB Mount) <sup>a</sup>	R <sub>thJA</sub>	-	-	40	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	-	60		

#### Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static					<u> </u>		1
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		200	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	ce to 25 °C, I <sub>D</sub> = 1 mA	-	0.30	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>		V <sub>GS</sub> = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>		= 200 V, V <sub>GS</sub> = 0 V V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	25 250	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	$V_{DS} = 100 \text{ V}$ $V_{GS} = 10 \text{ V}$	I <sub>D</sub> = 0.58 A b		1.2	250	Ω
Forward Transconductance	9fs		= 50 V, I <sub>D</sub> = 0.58 A	0.51	-	_	S
Dynamic	918	*05	- 00 1, 10 - 0.00 / 1	0.01			
Input Capacitance	C <sub>iss</sub>	1		_	140	I -	
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0 \text{ V}, \\ V_{DS} = 25 \text{ V}, \\ f = 1.0 \text{ MHz, see fig. 5}$		-	53	-	pF
Reverse Transfer Capacitance	C <sub>rss</sub>			-	15	_	
Total Gate Charge	Qq		I <sub>D</sub> = 3.3 A, V <sub>DS</sub> = 160 V,	-	-	8.2	nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V		-	-	1.8	
Gate-Drain Charge	Q <sub>gd</sub>	1	see fig. 6 and 13 b	-	-	4.5	
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD} = 100 \text{ V, } I_D = 3.3 \text{ A,}$ $R_g = 24 \Omega, R_D = 30 \Omega, \text{ see fig. } 10^\text{ b}$		-	8.2	-	ns
Rise Time	t <sub>r</sub>			-	17	-	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	14	-	
Fall Time	t <sub>f</sub>			-	8.9	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.0	-	-11
Internal Source Inductance	L <sub>S</sub>			-	6.0	-	- nH
Drain-Source Body Diode Characteristic	s					•	
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	0.96	^
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	7.7	A
Body Diode Voltage	V <sub>SD</sub>	$T_J = 25  ^{\circ}\text{C},  I_S = 0.96  \text{A},  V_{GS} = 0  \text{V}^{ \text{b}}$		-	-	2.0	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = 3.3 A, dl/dt = 100 A/µs b		-	150	310	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$			-	0.60	1.4	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic tu	ırn-on time is negligible (turn	on is dor	ninated b	y L <sub>S</sub> and	L <sub>D</sub> )

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width  $\leq 300~\mu s$ ; duty cycle  $\leq 2~\%$ .



### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

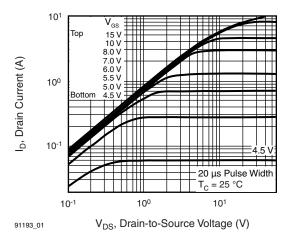


Fig. 1 - Typical Output Characteristics, T<sub>C</sub> = 25 °C

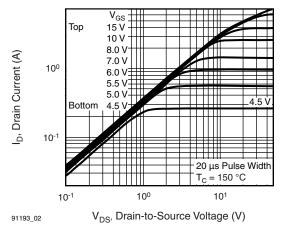


Fig. 2 - Typical Output Characteristics,  $T_C$  = 150 °C

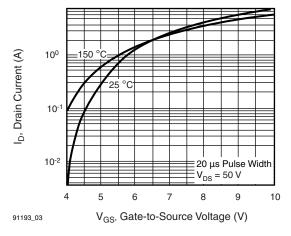


Fig. 3 - Typical Transfer Characteristics

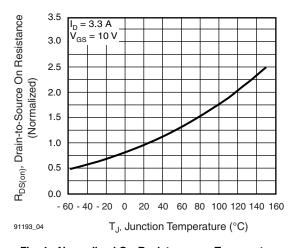


Fig. 4 - Normalized On-Resistance vs. Temperature

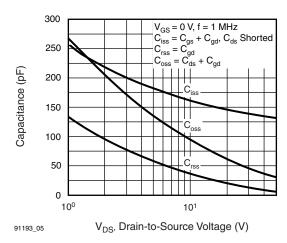


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

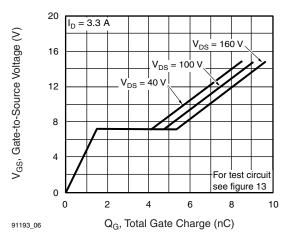


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



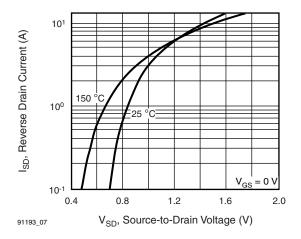


Fig. 7 - Typical Source-Drain Diode Forward Voltage

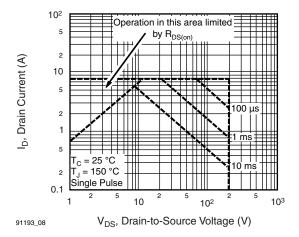


Fig. 8 - Maximum Safe Operating Area

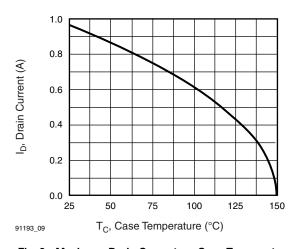


Fig. 9 - Maximum Drain Current vs. Case Temperature

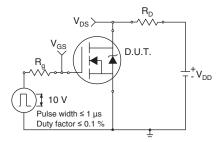


Fig. 10a - Switching Time Test Circuit

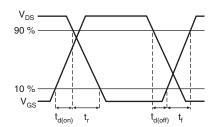


Fig. 10b - Switching Time Waveforms

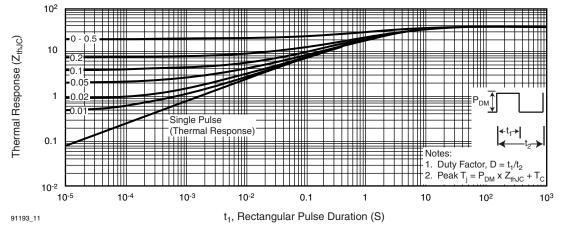


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



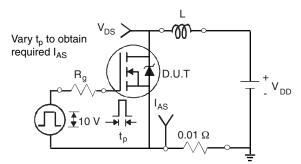


Fig. 12a - Unclamped Inductive Test Circuit

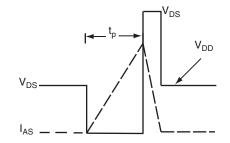


Fig. 12b - Unclamped Inductive Waveforms

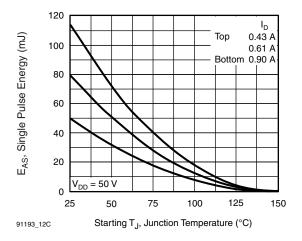


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

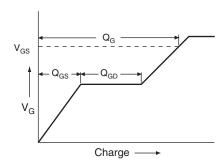


Fig. 13a - Basic Gate Charge Waveform

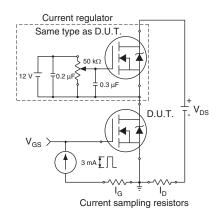
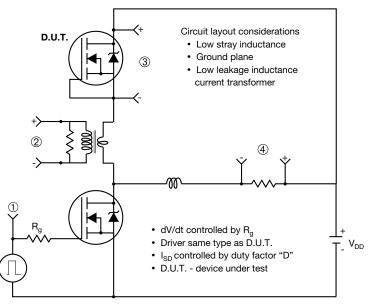


Fig. 13b - Gate Charge Test Circuit



### Peak Diode Recovery dV/dt Test Circuit



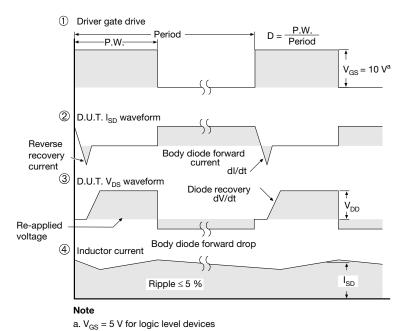
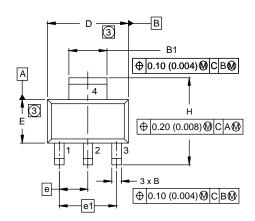
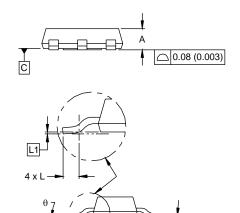


Fig. 14 - For N-Channel



### **SOT-223**





	MILLIMETERS		INCHES	
DIM.	MIN.	MAX.	MIN.	MAX.
Α	1.55	1.80	0.061	0.071
В	0.65	0.85	0.026	0.033
B1	2.95	3.15	0.116	0.124
С	0.25	0.35	0.010	0.014
D	6.30	6.70	0.248	0.264
Е	3.30	3.70	0.130	0.146
е	2.30 BSC		0.0905 BSC	
e1	4.60 BSC		0.181	BSC
Н	6.71	7.29	0.264	0.287
L	0.91	-	0.036	-
L1	0.061 BSC		0.002	4 BSC
θ	-	10'	-	10'

ECN: S-82109-Rev. A, 15-Sep-08

DWG: 5969

#### Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimensions are shown in millimeters (inches).
- 3. Dimension do not include mold flash.
- 4. Outline conforms to JEDEC outline TO-261AA.



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